Abstract

Now a days surface analysis have many application in various knowledge fields and one of the important field is material surface analysis. This approach is concentrated on the image enhancement to arise and detect small obstacles during the surface. This approach allows individual features and details of the specimen to become visible In addition many statistical measures are applied to evaluate this performance of this approach. In the obtained measures, the signal-to-noise ratio must be large enough to be interpreted in terms of the formation of a coherent image.

References

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**Index Terms**

| Computer Science | Image Processing |
Keywords

Image Analysis, Surface Analysis, Intensity Analysis, Optical Analysis and Statistical Measures.